

**Notice of References Cited**

Application/Control No.

10/529,517

Applicant(s)/Patent Under  
Reexamination  
IKEDA ET AL.

Examiner

HENOK G. HEYI

Art Unit

2627

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0003948 A1	01-2002	Himeno et al.	386/98
*	B	US-6,393,196 B1	05-2002	Yamane et al.	386/52
*	C	US-2004/0047589 A1	03-2004	Kim, Kwang Su	386/046
*	D	US-2004/0052275 A1	03-2004	Murakami et al.	370/503
*	E	US-6,778,760 B1	08-2004	Kagle, Jonathan C.	386/96
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	V				
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	X				

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